Open Peer Review on Qeios

Focused Ion Beam-Scanning Electron Microscope

National Cancer Institute

Source

National Cancer Institute. <u>Focused Ion Beam-Scanning Electron Microscope</u>. NCI Thesaurus. Code C78815.

An instrument that combines the use of a focused beam of gallium ions to etch or coat a sample with a scanning electron microscope to image the sample.